

**Search Notes**

Application/Control No.

10/595,148

Examiner

Hai H. Huynh

Applicant(s)/Patent under  
Reexamination

NEISE ET AL.

Art Unit

3747

**SEARCHED**

Class	Subclass	Date	Examiner
123	399	3/26/2007	HHH
123	337	3/26/2007	HHH
251	305	3/26/2007	HHH

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East	3/26/2007	HHH